

EAST Search History

S7	3833	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:43
S8	1149	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 07:47
S9	545	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 09:36
S10	32	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 11:15

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S11	30	("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn. and (range window)	USPAT	OR	ON	2006/01/11 09:37
S12	104	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 11:16
S13	2	S11 and S12	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 13:54
S14	1	S11 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 18:10
S15	26	S12 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/12 12:07
S16	82	"5657332"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 16:29

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S17	2	"5657332".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 17:34
S18	6	S10 not S15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 17:34
S19	125	non-deterministic with (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 17:21
S20	3842	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 07:48
S21	1114	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and ((don?t adj care) mask\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 07:49
S22	1150	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 07:49
S23	892	S22 not S21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 07:50
S24	636	S22 not S21	USPAT	OR	ON	2006/01/13 07:50
S25	0	S22 not S21	IBM_TDB	OR	ON	2006/01/13 07:50

EAST Search History

S26	0	S22 not S21	DERWENT	OR	ON	2006/01/13 12:03
S27	2	"20040225934"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 12:06
S28	2	"20050053093"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 12:06
S29	8	FUKUSHIMA.in. and (britt-harris). xa.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/13 12:07
S30	4	(harris britt).xa. and wafer.clm. and "714"/\$.ccor.	USPAT	OR	ON	2006/01/17 11:13
S31	147	(harris.xa. britt.xa.) and "714"/\$. ccor.	USPAT	OR	ON	2006/01/18 11:47
S32	552	"714"/724.ccor.	USPAT	OR	ON	2006/01/18 12:14
S33	194	"714"/727.ccor.	USPAT	OR	ON	2006/01/18 12:21
S34	44	"714"/790.ccor.	USPAT	OR	ON	2006/01/18 12:21
S35	9	"081329"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 17:21
S36	62	mask\$4 and (compare comparing compared comparison) and (test testing tester tested) and (bus adj layout)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 20:50
S37	1	(compare comparing compared comparison) and (test testing tester tested) and ((bus adj layout) near2 file)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 20:51
S38	1	(compare comparing compared comparison) and (test testing tester tested) and ((bus adj layout) with file)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 20:51
S39	1	(compare comparing compared comparison) and (test testing tester tested) and ((bus adj layout) same file)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 21:30

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S40	12	"875567"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/18 21:30
S41	15264	(sequence order) same (compare compared comparisin comparing) same (expected expect expecting)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/11 15:29
S42	10733	((sequence order) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/11 15:30
S43	912	((sequence order) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/11 15:30
S44	239	((sequence order) with (receiv\$)) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/11 16:09
S45	225	((sequence order) with (receiv\$)) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet and (generate generated generation generating)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/11 16:09
S46	223	((sequence order) with (receiv\$)) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet and (generate generated generation generating) and (pass fail passing failing passed failed failure good bad error erroneous)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/11 16:11
S47	108	((sequence order) with (receiv\$)) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet and (generate generated generation generating) and (pass fail passing failing passed failed failure good bad error erroneous)	USPAT	OR	ON	2006/07/11 16:16

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S48	102	((sequence order) with (receiv\$)) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet and ((generate generated generation generating) with (test data signal vector)) and (pass fail passing failing passed failed failure good bad error erroneous)	USPAT	OR	ON	2006/07/11 16:17
S49	65	((sequence order) with (receiv\$)) same (compare compared comparisin comparing) same (expected expect expecting)) and (test testing tester tested) and packet and ((generate generated generation generating) near2 (test data signal vector)) and (pass fail passing failing passed failed failure good bad error erroneous)	USPAT	OR	ON	2006/07/12 09:51
S50	3038	(test adj condition).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/12 09:52
S51	402	(test adj condition).ab. and (temperature burn-in).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/12 09:53

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	49	("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn.	USPAT	OR	ON	2006/07/11 15:26
S2	42	("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn. and (generat\$) and compar\$	USPAT	OR	ON	2006/01/09 10:06

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S3	39	("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn. and (generat\$) and compar\$ and test\$	USPAT	OR	ON	2006/01/09 10:07
S4	37	("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn. and (generat\$) and compar\$ and test\$ and result	USPAT	OR	ON	2006/01/10 08:28
S5	62940	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and result	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:41
S6	4691	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:42